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(54) Thick film silver termination composition

(57) The present invention is directed to thick film silver termination composition comprising, based on the total composition; a. 60-80% wt. silver powder; b. 0.1-15% wt. fine particles of glass binder having a softening point of 400 to 650°C and an absolute viscosity of less than 10⁶ poise at firing temperature; c. 0.1-5% wt. negative temperature coefficient of resistance (TCR) drivers;

and wherein a, b, and c are dispersed in an organic vehicle. The invention is further to a composition wherein the negative TCR drivers may be substituted by hydrides of metals of the fourth and fifth groups of the periodic table. The negative TCR drivers may also be substituted with select metal powders, which may be combined with the hydrides or drivers.

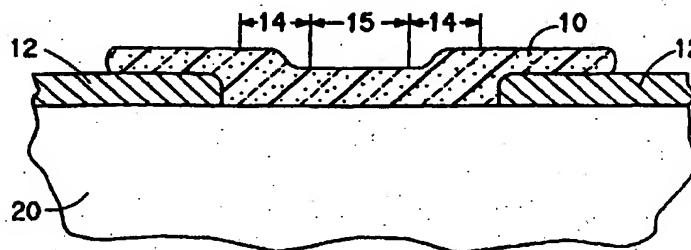


FIG. 1

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Description**FIELD OF THE INVENTION**

- 5 [0001] This invention relates to thick film silver termination compositions containing negative Temperature Coefficient of Resistance (TCR) drivers or metal hydrides.

BACKGROUND OF THE INVENTION

- 10 [0002] Since it has become the trend in the industry to make smaller and cheaper electronic devices, it has become necessary to reduce the size and cost of the components, such as thick film chip resistors and hybrid resistors used in such devices.

- [0003] This has been accomplished by using low cost Ag-rich terminations to terminate small geometry resistors which are less than 2 mm in length. The observed TCR of a resistor is not only a function of the resistor ink itself but also is dependent upon the termination material such as the conductor runner. As used herein, TCR = (Temperature coefficient of resistivity) - (Thermal expansion coefficient). A typical resistor/conductor combination is illustrated in Fig. 1 including a substrate 20 having a resistor 10 printed thereon which terminates at each end to a conductor runner 12. Also illustrated are interface regions 14 near each end of the resistor near the termination point. The interface region 14 is the area of the resistor susceptible to diffusion of silver from the conductor.

- 20 [0004] In preparation of the combination, the conductor is printed and fired prior to printing and firing of the resistor material. The conductor may be fired in a conventional manner, for example, at about 850°C peak in a 30 minute cycle. During the resistor firing, the conductor material diffuses into the resistor to form an interface region 14 that has electrical properties different from the bulk of the resistor 16. The impact of this interface region on the observed TCR will depend upon the extent of the diffusion of the conductor material into the resistor and the resistor length. The longer the resistor, the less influence on the observed TCR. For low value resistors, the high TCR of the conductor runner will raise the observed TCR above the bulk value of the resistor. Ag conductor runners will have the greatest impact on the observed TCR.

- [0005] As discussed above, there are performance trade-offs in using Ag terminations with short resistors. Such resistors exhibit significant problems resulting from the diffusion of Ag from the terminations into the short resistor. One of the problems is a significant "length effect" where the Resistance (R) and Temperature Coefficient of Resistance (TCR) of the resistor is dependent on the length of the resistors. Length effects can be reduced by using Pd/Ag or gold terminations to minimize resistor/termination interactions. However, this approach is not favored for obvious cost reasons.

- 30 [0006] Figure 2 is an illustration of "length effect" in a Ag terminated thick film resistor. It shows that the Resistance decreases and the TCR increases as the length of the resistor is decreased below 2 mm. If Ag diffusion into the resistor is prevented, R and TCR of the resistor are independent of length and for design purposes R obeys the basic thick film equation:

$$R = R_s \cdot n$$

- 40 where:

R = resistance

R_s = sheet resistance

n = l/w = no. of squares

- 45 In addition to + or - 1% tolerance in R, state of the art resistors are currently manufactured to + or - 100 ppm/C tolerance in TCR. In order to obtain even tighter tolerances in TCR without increasing resistor size and cost, new compositions are needed for terminations which will reduce length effect in Ag-terminated resistors. Therefore, the present invention is a low cost method to reduce the length effect of Ag terminated low ohm (<100 ohm) RuO₂ resistors through the addition of negative TCR drivers and/or metal hydrides to the Ag termination composition.

BRIEF DESCRIPTION OF THE DRAWINGS

- [0007] Fig. 1 is a schematic representing a typical conductor/resistor combination.
- [0008] Fig. 2 is a graphical illustration representing illustration of "length effect" in a Ag terminated thick film resistor.
- 55 [0009] Fig. 3 is a graphical illustration representing the HPCR as a function of resistor length for a nominal 10 ohm resistor sequentially fired over various Ag-rich terminations.
- [0010] Fig. 4 is a graphical illustration representing the length effect of a 10 ohm resistor terminated with a stand silver termination (Termination A) to the length effect obtained with a TiH₂ doped Ag termination on the present invention.

SUMMARY OF THE INVENTION

[0011] The present invention is directed to thick film silver termination composition comprising, based on total composition;

- a. 60-80 %wt. silver powder;
 - b. 1-15 %wt. fine particles of glass binder having a softening point of 400 to 650°C and an absolute viscosity of less than 10^6 poise at firing temperature;
 - c. 1-5% wt. negative TCR driver; and
- wherein a, b, and c are dispersed in an organic vehicle.

[0012] The invention is further to a composition wherein the negative TCR drivers may be substituted by hydrides of metals of the fourth and fifth groups of the periodic table. The negative TCR drivers are may also be substituted with select metal powders or the powders may be combined with the hydrides or drivers.

DETAILED DESCRIPTION OF THE INVENTION

[0013] In order to minimize length effect, Ag-rich termination compositions are employed comprising Ag powder as the conductive, lead-boro-silicate glass as the inorganic binder and a negative TCR driver(s), dispersed in an organic screen printing vehicle. TCR drivers may be used separately or may be used in combinations. The TCR driver(s) may be found in the glass or may be added directly to the Ag termination composition during milling or it may be found in both. The function of the TCR driver is to compensate for the effects of Ag diffusion on the R and TCR of the resistor. The TCR driver is present in an amount equal to or less than five weight percent of total solids in termination.

[0014] As used herein, TCR of a resistor is a measurement of the resistance dependence on temperature.

[0015] Hot TCR (HTCR) and Cold TCR (CTCR) are generally expressed in ppm/°C and are defined by (1) and (2).

$$\text{HTCR in ppm/}^\circ\text{C} = \frac{R_{125} - R_{25}}{R_{25}(125 - 25)} \times 10^6 \quad (1)$$

$$\text{CTCR in ppm/}^\circ\text{C} = \frac{R_{-55} - R_{25}}{R_{25}(-55 - 25)} \times 10^6 \quad (2)$$

where

R_{25} = Resistance in ohms/sq at 25°C

R_{125} = Resistance in ohms/sq at 125°C

R_{-55} = Resistance value in ohms/sq at -55°C

[0016] Although adding negative TCR drivers (e.g. oxides of Ti, Nb, Mn, Fe, Co, Cr, W, Mo, V and Sb) to Ag terminations will reduce the length effect of Ag terminated RuO_2 resistors, the hydrides of metals of the fourth and fifth groups of the periodic table (e.g., TiH_2 , ZrH_2 , HfH_2 , CbH , ThH_4 and TaH) have been found to be particularly effective as drivers. It is presumed that these hydrides decompose and provide a reducing atmosphere which may inhibit formation of Ag^+ which is very mobile and diffuses readily into the resistor glass. After decomposition the metal formed is very reactive so it alloys with Ag which is abundant in the termination. Since these metals are strong reducing agents, the oxidation of Ag to Ag^+ is further inhibited. After firing, the reactive metal is internally oxidized in the Ag, so it is uniformly distributed and available for diffusion into the resistor glass (along with any Ag^+ that forms).

[0017] The TCR driver that diffuses into the resistor glass increases R and decreases TCR, so it compensates for the effect of Ag^+ diffusion which decreases R and increases TCR. By suitably adjusting the type and concentration of TCR driver in the termination, the length effect caused by Ag^+ diffusion into the resistor can be essentially eliminated. More specific examples of TCR drivers are Sb_2O_3 , Fe_2O_3 , Fe_3O_4 , WO_3 , Nb_2O_3 , V_2O_5 , Cr_2O_3 , MoO_3 , TiO_2 , Mn_2O_3 , MnO_3 , Ta_2O_5 , and Co_2O_3 .

[0018] Furthermore, metallic powders such as Ti, Nb, Mn, Fe, Co, Cr, W, Mo, V, and Sb added to the Ag termination alone or in combination with one or more of the above hydrides or TCR drivers are also very effective in minimizing length effect. It is believed the reducing atmosphere created by hydride decomposition moderates their rate of oxidation and enables them to act as reducing agents to inhibit formation of Ag^+ . After eventual oxidation, they diffuse into the resistor glass and serve as negative TCR drivers to compensate for R/TCR changes caused by Ag^+ diffusion into the

resistor.

[0019] The silver powders can have various morphologies such as flake or non-flake. The non-flake powders can be irregularly shaped or spherical. Preferably, fine flake or spherical silver powders with 1 μm average particle size are utilized.

[0020] Another component of the silver compositions of this invention is a low softening point glass at .1-15 wt % of the total composition and preferably at .1-10 wt % and more preferably at .1-2 wt %. By low-softening point glass is meant a glass having a softening point below 650°C and preferably below 500°C, as measured by the conventional fiber elongation method (ASTM C 338-57). Therefore, the glass binder in the Ag termination should have a softening point in the range of 400°C-650°C. Its function is to wet the conductive in order to aid coalescence and sintering of the Ag particles and to provide a bond to the substrate. The glass utilized in this invention also has to have a low viscosity at the firing temperature. Glasses having an absolute viscosity of less than 10^6 poise at the firing temperature satisfy the requirements for the silver compositions by facilitating the transport of the inorganic materials from the composition into the interior of the substrate body along the grain boundaries and voids.

[0021] Typical examples of glasses meeting the above criteria are lead bismuth borate glasses containing, by weight %, Bi_2O_3 , 40-60; PbO , 28-37; and B_2O_3 , 3-32. A particularly preferred glass contains Bi_2O_3 , 60%; PbO , 37%; and B_2O_3 , 3%. In addition, lead-boro-silicate glasses modified with Al_2O_3 , CaO , MgO , ZnO , TiO_2 , ZrO_2 , etc. are suitable provided they are stable, durable, and have a softening point in the range indicated. Examples of other suitable low softening point glasses include: Pb-Zn alumino-borosilicate, Pb Zn borosilicate, Zn-Cu borosilicate, alkali borosilicate, alkali-alumino borosilicate, Bi borosilicate, Bi-Zn borosilicate. The glass binder should yield good conductivity, adhesion and densification of the Ag termination when fired in the range of 800-900°C, with a preferred firing temperature of 850°C.

[0022] The glasses are prepared by conventional glass-making techniques, by mixing the desired components (or precursors thereof, e.g., H_3BO_3 for B_2O_3) in the desired proportions and heating the mixture to form a melt. As is well known in the art, heating is conducted to a peak temperature and for a time such that the melt becomes entirely liquid, and gaseous evolution has ceased. In the present work the components are premixed by shaking in a jar and then melted in a Pt crucible at approximately 1000°C. The melt is then poured into cold water and, after separation from the quench water, the crude frit is freed from residual water by drying in an oven. The crude frit is then ball-milled for 40 hours in water using alumina balls. After discharging the milled frit slurry from the mill, the excess solvent is removed by decantation and the frit powder is air dried at room temperature. The dried powder is then screened through a 60-mesh screen to remove any large particles.

[0023] The glass powder should have a particle size less than 10 μm and preferably less than 5 μm . Likewise, the Ag powder and TCR driver or its precursor should have a particle size of less than 5 μm and preferably ca. 1 μm in diameter.

[0024] The inorganic solids content of the silver composition of this invention (silver, glass and inorganic material or precursor thereof) is dispersed in an organic vehicle to form printable composition pastes. The inorganic particles are mixed with an essentially inert liquid medium (vehicle) by mechanical mixing using a planetary mixer, then dispersed on a three roll mill to form a paste-like composition having suitable consistency and rheology for screen printing. The latter is printed as a "thick film" on conventional ceramic substrates in the conventional manner.

[0025] Any essentially inert liquid may be used as the vehicle. Various organic liquids, with or without thickening and/or stabilizing agents and/or other common additives, may be used as the vehicle. Exemplary of organic liquids which can be used are the aliphatic alcohols, esters of such alcohols, for example, acetates and propionate, terpenes such as pine oil, terpeneol and the like, solutions of resins such as the polymethacrylates or lower alcohols and solutions of ethyl cellulose in solvents such as pine oil and the monobutyl ether of ethylene glycol monoacetate. A preferred vehicle is based on ethyl cellulose resin and a solvent mixture of alpha-, beta-, and gamma terpeneols (generally 85-92% alpha-terpeneol containing 8-15% beta- and gamma-terpeneols). The vehicle may contain volatile liquids to promote fast setting after application to the substrate.

[0026] The ratio of vehicle to solids in the dispersions can vary considerably and depends upon the manner in which the dispersion is to be applied and the kind of vehicle used. Preferably, to achieve good coverage, the dispersions will contain complementarily about 60-90% solids and 40-10% vehicle, as described above. The compositions of the present invention may, of course, be modified by the addition of other materials which do not affect its beneficial characteristics. Such formulations is well within the skill of the art.

[0027] The pastes are conveniently prepared on a three-roll mill. The viscosity of the pastes is typically within the following ranges when measured on a Brookfield HBT viscometer at low, moderate, and high shear rates:

Shear Rate (sec ⁻¹)	Viscosity (Pa · s)	
0.2	100-5000	
	300-2000	Preferred
	600-1500	Most Preferred
4	40-400	
	100-250	Preferred
	140-200	Most Preferred
40	10-150	
	25-120	Preferred
	50-100	Most Preferred

The amount of vehicle is determined by the final desired formulation viscosity.

[0028] The silver compositions of this invention can be printed as film onto the substrates either by using an automatic printer or a hand printer in the conventional manner. Preferably, automatic screen stenciling techniques are employed, using a 200-mesh screen.

[0029] The ability of Ag terminations containing negative TCR drivers or metal hydrides to substantially reduce or eliminate the length effect in low ohm thick film resistors is limited to resistors containing RuO₂ as the main conductive phase. As presently practiced in the industry, low ohm resistances below 100 ohms/sq. is achieved by adding Pd/Ag in amounts greater than 10% by weight and in combination with RuO₂ as the conductive phase. Such resistors exhibit a large length effect which is not responsive to the addition of negative TCR drivers in the terminations.

[0030] Likewise, high ohm resistors with sheet resistances above 100 ohm/sq. generally use glasses with higher viscosities and softening points than those used for low ohm resistors. Such resistor glasses tend to slow the rate of Ag+ diffusion from the termination into the resistor which causes smaller length effects than observed in higher ohm resistors.

[0031] Therefore, the main application for the current invention is in low ohm resistors where low viscosity, low softening point glasses must be used to disperse the large amount of RuO₂ conductive phase required to obtain low resistance values. Although the new terminations of the current invention may be used with high ohm resistors, the improvements in length effect observed are not as great because diffusion of the negative TCR driver (and Ag+) through the higher viscosity glass at the 850°C firing temperature is substantially reduced.

Formulation and Application

[0032] In the preparation of the compositions of the present invention, the particulate inorganic solids are mixed with the organic medium and dispersed with suitable equipment, such as three-roll mill, to form a suspension, resulting in a composition for which the viscosity will be in the range of about 100-200 pascal-seconds at a shear rate of 4 sec⁻¹.

[0033] In the examples which follow, the formulation was carried out in the following manner:

[0034] The ingredients of the paste are weighed together in a container. The components are then vigorously mixed to form a uniform blend; then the blend is passed through dispersing equipment, such as a three-roll mill, to achieve a good dispersion of particles. A Hegman gauge is used to determine the state of dispersion of the particles in the paste. This instrument consists of a channel in a block of steel that is 25 µm deep (1 mil) on one end and ramps up to zero depth at the other end. A blade is used to draw down paste along the length of the channel. Scratches appear in the channel where the agglomerates' diameter is greater than the channel depth. A satisfactory dispersion will give a fourth scratch point of 10-18 µm typically. The point at which half of the channel is uncovered with a well dispersed paste is between 3 and 8 µm typically. Fourth scratch measurement of >20 µm and "half-channel" measurements of >10 µm indicate a poorly dispersed suspension.

[0035] The compositions are then applied to a substrate, such as alumina ceramic, usually by the process of screen printing, to a wet thickness of about 30-80 microns, preferably 35-70 microns, and most preferably 40-50 microns. The compositions of this invention can be printed onto the substrates either by using an automatic printer or a hand printer in the conventional manner, preferably automatic screen printing techniques are employed using a 200- to 325-mesh screen. The printed pattern is then dried at below 200°C, about 150°C, for about 5-15 minutes before firing. Firing to effect sintering of both the inorganic binder and the finely divided particles of metal is preferably done in a well ventilated

belt conveyor furnace with a temperature profile that will allow burnout of the organic matter at about 300°-600°C, followed by a period of maximum temperature of about 800°-1000°C, lasting about 5-15 minutes, followed by a controlled cooldown cycle to prevent over sintering, unwanted chemical reactions at intermediate temperatures or substrate fracture which can occur from too rapid cool down. The overall firing procedure will preferably extend over a period of about 30-60 minutes, with 10-25 minutes to reach the firing temperature of 850°C, about 10 minutes at the firing temperature and about 10-25 minutes in cool down. In some instances, total cycle times can be used as short as 20-30 minutes by conventional firing and 7-14 minutes of infrared firing.

[0036] The present invention will be described in further detail by giving practical examples. The scope of the present invention, however, is not limited in any way by these practical examples.

[0037] All values given in the tables are weight percent based on total composition.

EXAMPLES

[0038] The following compositions are commercially available silver termination compositions, listed as follows:

Composition A - Silver termination composition 5426

Composition B - Silver termination composition QS171

Composition C - Silver termination composition 6160

Compositions A, B and C are available from E. I. du Pont de Nemours and Company, Wilmington, DE.

[0039] Also, as shown in Table 1, are additional silver termination compositions which may be utilized in the practice of the invention.

TABLE 1

	D	E	F	G	H	I
Ag	73.35	72.40	72.40	72.40	72.40	72.40
Pd	0.55	0.60	0.60	0.60	0.60	0.60
Bi ₂ O ₃						
PbO ₂						
Cu ₂ O						
Cr						1.00
*W			1.00			
*Wsi ₂				1.00		
*TiH ₂	1.55	1.04	0.69	0.69	.897	0.69
(ethyl cellulose/terpineol) Organic Vehicle	23	24.75	24.5	24.5	25.05	24.5
Frit I		0.67	0.45	0.45	0.585	0.45
Frit II	0.31					
Frit III	0.93					
Frit IV		0.09	0.06	0.06	0.78	0.06
Frit V		0.23	0.15	0.15	0.195	0.15
Frit VI	0.31	0.22	0.15	0.15	0.195	0.15

*TCR Drivers

[0040] Frit compositions used in compositions D-I are found in Table 2.

TABLE 2

wt% based on total glass composition						
	I	II	III	IV	V	VI
Oxide						
PbO	55.9	6.6	50.96	78.1		
SiO ₂	2.8	23	26.06		24.94	
B ₂ O ₃	8.1	8.5	6.94		6.46	
Al ₂ O ₃	4.7	2.5	6.69			
*TiO ₂	3.3		4.56		13.77	
ZnO			2.79			
CuO						9.1
*MnO					54.83	
CaO						
GeO ₂				21.9		90.9
Bi ₂ O ₃						
	100	100	100	100	100	100

*TCR Drivers

[0041] In Examples 1 through 67 -- silver terminations are printed on nominal 10 Ohm resistors (R1-R4) used to demonstrate the general utility of the present invention in significantly reducing the "length effect" commonly observed in short resistors terminated with Ag. The conductive phase in the resistors is RuO₂, typically present in amounts greater than 40% RuO₂ by weight of solids, in order to obtain the low 10 ohm/sq. sheet resistance. Although the glass chemistries of the resistors are significantly different, the resistor glasses have a low softening point in the 400-650°C range and a low viscosity at a range of 800-900°C firing temperature which allows for good wetting, dispersion and densification by sintering of the RuO₂ conductive phase. Resistor compositions R2 and R3 are commercial compositions and identified as follows:

R2 - Resistor composition 2011

R3 - Resistor composition is a 50/50 by weight blend of 2011 and 1711

Compositions R2 and R3 are available from E. I. du Pont de Nemours and Company, Wilmington, DE.

[0042] Compositions for R1 and R4 are given in Table 3.

TABLE 3

Components	R1 - wt%	Components	R4 - wt%
RuO ₂	41.04	RuO ₂	40.32
Ag ₂ O	1.44	Ag ₂ O	1.44
MnO ₂	0.36	TiO ₂	1.44
a	2.16	a	2.16
b	2.88	d	14.40
c	4.68	e	8.64
d	19.44	f	3.60
*Organic Vehicle	28.00	*Organic Vehicle	28.00

*Organic Vehicle - ethyl cellulose and terpineol

[0043] Formulations for a-f are given in TABLE 4.

TABLE 4

	a	a ₁	b	c	d	e	f
Al ₂ O ₃		1.1					
BaO							20.90
BiO ₂		75.1					
B ₂ O ₃			18.24	6.80	8.5	3.08	28.02
CuO	14.0					2.76	
CaO		2.4					5.96
MgO							5.50
MnO				9.41			
MnO ₂	21.5						
Nb ₂ O ₅			16.32				
P ₂ O ₅							1.86
PbO		10.9	6.33	52.80	66.0	58.90	
SiO ₂		9.3	3.84	18.40	23.0	29.52	11.19
TiO ₂				10.59			
ZnO	14.5	1.2	55.28			2.59	9.34
ZrO ₂							8.62
a ₁	50						

TABLE 5																
Ex. No.	Resistor No.	Termination Composition	Additive Wt %	SEQUENTIAL FIRED TERMINATION/RESISTOR						dHTCR (0.25-1.25mm)	COFIRED TERMINATION/RESISTOR				dHTCR 0.25-1.25mm	dCTCR 0.25-1.25mm
				HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	HTCR 0.25mm	HTCR 1.25mm		CTCR 0.25mm	CTCR 1.25mm				
1	R1	A	None	280	52	219	-18	228	237	258	47	193	-23	211	216	
2	R1	A+	1.5% TiO ₂	110	115	86	90	-5	-4	-6	-1	-91	-77	-5	-14	
3	R1	A+	3.0% TiO ₂	-194	-73	-302	-160	-121	-142	-237	-87	-350	-177	-150	-173	
4	R1	A+	4.0% Nb ₂ O ₅	124	21	55	-52	103	107	90	14	18	-59	76	77	
5	R1	A+	4.0% MnO ₂	138	32	57	-41	106	98	100	27	13	-49	73	62	
6	R1	B	None	470	72	439	5	398	434	550	79	522	13	471	509	
7	R1	B+	1.5% TiO ₂	111	113	79	75	-2	4	174	35	112	-36	139	148	
8	R1	B+	3.0% TiO ₂	-146	-58	-248	-143	-88	-105	-175	-57	-278	-141	-118	-117	
9	R1	B+	4.0% Nb ₂ O ₅	336	53	290	-16	283	306	356	58	309	-11	298	320	
10	R1	B+	4.0% MnO ₂	300	56	243	-14	244	257	329	53	272	-18	276	290	
11	R1	C	None	259	47	204	-24	212	228	273	47	217	-24	226	241	
12	R1	C+	1.5% TiO ₂	-100	-138	-162	-202	38	40	-50	-15	-140	-93	-35	-47	
13	R1	C+	3.0% TiO ₂	-474	-247	-634	-367	-227	-267	-422	-196	-570	-308	-226	-262	
14	R1	C+	4.0% Nb ₂ O ₅	95	23	22	-51	72	73	61	5	-15	-70	56	55	
15	R1	C+	4.0% MnO ₂	137	26	58	-49	111	107	146	25	67	-49	121	116	
16	R2	A	None	158	17	84	-72	141	156	138	17	52	-72	121	124	
17	R2	A+	1.5% TiO ₂	-47	-45	-117	-116	-2	-1	-42	-29	-145	-124	-13	-21	

TABLE 5 (cont'd.)																
Ex. No.	Resistor No.	Termination Composition	Additive Wt %	SEQUENTIAL FIRED TERMINATION/RESISTOR						dHTCR (0.25-1.25mm)	COFIRE TERMINATION/RESISTOR				dHTCR 0.25-1.25mm)	dCTCR
				HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	
18	R2	A+	3.0% TiO ₂	-259	-60	-222	-158	-199	-64	-151	-67	-151	-67	-166	-84	-105
19	R2	A+	4.0% Nb ₂ O ₅	-121	-46	-234	-142	-75	-92	-112	-51	-112	-51	-148	-61	-83
20	R2	A+	4.0% MnO ₂	153	13	70	-75	140	145	151	14	151	14	65	137	140
21	R2	B	None	337	39	274	-46	298	-235	427	20	427	20	370	407	410
22	R2	B+	1.5% TiO ₂	200	204	169	173	-4	35	180	-17	180	-17	106	197	175
23	R2	B+	3.0% TiO ₂	-19	-31	-116	-124	12	85	-1	6	-1	6	-99	-7	8
24	R2	B+	4.0% Nb ₂ O ₅	66	-2	-23	-91	68	21	120	31	120	31	82	89	113
25	R2	B+	4.0% MnO ₂	287	31	218	-55	256	-187	319	19	319	19	250	300	306
26	R2	C	None	173	18	94	-69	155	163	196	19	196	19	122	177	190
27	R2	C+	1.5% TiO ₂	69	7	36	-34	62	70	-54	-20	-54	-20	-152	-34	-39
28	R2	C+	3.0% TiO ₂	-171	-74	-301	-181	-97	-120	-14	-65	-14	-65	-165	51	-92
29	R2	C+	4.0% Nb ₂ O ₅	-99	-37	-210	-133	-62	-77	-96	-45	-96	-45	-206	-51	-64
30	R2	C+	4.0% MnO ₂	171	17	90	-71	154	161	185	17	185	17	103	168	176
31	R3	A	None	98	-32	11	-122	130	133	127	-24	127	-24	54	151	166
32	R3	A+	3.0% TiO ₂	-270	-199	-408	-320	-71	-88	-294	-165	-294	-165	-442	-129	-162
33	R3	A+	4.0% Nb ₂ O ₅	-152	-88	-276	-187	-64	-89	-154	-80	-154	-80	-281	-74	-103
34	R3	A+	4.0% MnO ₂	67	-37	-27	-128	104	101	98	-28	98	-28	8	126	136

TABLE 5 (cont'd.)

TABLE 5 (cont'd.)																	
Ex. No.	Resistor No.	Termination Composition	Additive Wt %	SEQUENTIAL FIRED TERMINATION/RESISTOR						dTTCR (0.25-1.25mm)	COFIED TERMINATION/RESISTOR						dTTCR 0.25-1.25mm)
				HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	HTCR 0.25mm	HTCR 1.25mm		CTCR 0.25mm	CTCR 1.25mm					
35	R3	B	None	226	-5	148	-91	231	281	1	214	-83	280	297			
36	R3	B+	3.0%	-60	-77	-175	-174	17	-113	-101	-233	-203	-12	-30			
			TiO ₂														
37	R3	B+	4.0%	6	-48	-93	-141	54	60	-36	-29	-126	96	97			
			Nb ₂ O ₅														
38	R3	B+	4.0%	193	-18	115	-106	211	226	-11	154	-98	237	252			
			MnO ₂														
39	R3	C	None	108	-23	28	-110	131	135	-12	65	-98	147	163			
40	R3	C+	3.0%	-449	-334	-616	-478	-115	-431	-270	-594	-402	-161	-192			
			TiO ₂														
41	R3	C+	4.0%	-254	-107	-389	-209	-147	-257	-110	-396	-213	-147	-183			
			Nb ₂ O ₅														
42	R3	C+	4.0%	90	-27	-2	-116	117	99	-21	8	-108	120	116			
			MnO ₂														

TABLE 6

Ex. No.	Resistor No.	Termination Composition	Additive Wt %	SEQUENTIAL FIRED TERMINATION/RESISTOR						COFIED TERMINATION/RESISTOR			JHTCR 0.25-1.25mm	JHTCR 0.25-1.25mm
				HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	dHTCR (0.25-1.25mm)	dCTCR	HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	
43	R1	A	None	280	52	219	-18	228	237	258	47	193	-23	211
44	R1	A+	3% NbH	141	22	69	-52	119	121	132	28	57	-46	104
45	R2	A	None	158	17	84	-72	141	156	138	17	52	-72	121
46	R2	A+	3% NbH	-27	-44	-132	-141	17	9	77	-5	-16	-98	82
47	R3	A	None	98	-32	11	-122	130	133	127	-24	54	-112	151
48	R3	A+	3% NbH	32	-57	-52	-154	89	102	18	-54	-75	-151	72
49	R1	C	None	259	47	204	-24	212	228	273	47	217	-24	226
50	R1	C+	3% NbH	50	15	-30	-62	35	32	57	10	-25	-67	47
51	R2	C	None	173	18	94	-69	155	163	196	19	122	-68	177
52	R2	C+	3% NbH	-101	-35	-211	-131	-66	-80	-94	-95	-192	-176	1
53	R3	C	None	108	-23	28	-110	131	138	135	-12	65	-98	147
54	R3	C+	3% NbH	-232	-111	-366	-216	-121	-150	-246	-128	-369	-235	-118
55	R2	A	None	158	17	84	-72	141	156					
56	R2	A+	1% TiH ₂	110	19	28	-68	91	96					
57	R2	A+	3% TiH ₂	-99	-18	-205	-108	-81	-97					
58	R2	A+	3% Nb ₂ O ₅	50	9	-36	-78	41	42					
59	R2	A+	3% MnTiO ₃	41	8	-51	-80	33	29					
60	R2	A+	3% TiC	102	14	15	-73	88	88					
61	R2	A+	3% Ag ₂ WO ₄	59	0	-27	-88	59	61					
62	R4	A	None	273	109	260	88	164	172					
63	R4	A+	3% Nb ₂ O ₅	218	105	200	84	113	116					
64	R4	A+	3% MnTiO ₃	74	78	25	50	-4	-25					
65	R4	A+	3% TiC	215	102	194	81	113	113					

TABLE 6 (cont'd.)

Ex. No.	Resistor No.	Termination Composition	Additive Wt %	SEQUENTIAL FIRED TERMINATION/RESISTOR				COFIRED TERMINATION/RESISTOR		dHTCR (0.25-1.25mm)	dCTCR (0.25-1.25mm)
				HTCR 0.25mm	HTCR 1.25mm	CTCR 0.25mm	CTCR 1.25mm	HTCR 0.25mm	CTCR 1.25mm		
66	R4	A+	3% Ag ₂ WO ₄	121	76	98	53			45	
67	R4	A+	3%TH ₂	129	81	104	57			48	

[0044] Referring to TABLES 5 and 6, for comparison purposes it is convenient to use the difference in TCR (dHTCR and dCTCR) between resistors 0.25 mm and 1.25 mm in length as a measure of length effect. DHTCR and dCTCR values are found in columns labeled as such in Table 5 for sequentially fired terminations/resistors and for cofired terminations/resistors.

[0045] The data in TABLE 5 shows that the TCR of a low ohm RuO_2 resistor depends on the composition of the Ag termination and the geometry (length) of the resistor. Examples in TABLE 5 are for three nominal 10 ohm resistors 10R1, 10R2 and 10R3 terminated with Ag-rich terminations A, B, and C.

[0046] As shown in TABLE 5, when TiO_2 , Nb_2O_5 and MnO_2 TCR drivers are added to terminations A, B, and C, the TCR of the resistor is negatively biased versus the undoped termination. Data are given for resistors 0.25 and 1.25 mm in length sequentially fired and cofired with the termination in a standard $850^\circ\text{C}/30'$ profile. The TCR's of resistors terminated with A, B, and C containing no additives are also shown for comparison purposes.

[0047] In every case, the high positive TCR of the short 0.25 mm resistor is biased more negatively in TCR by the driver additive to the termination. Therefore, by controlling the concentration of TCR driver to the termination, the TCR of the resistor can be adjusted to a tolerance of ± 100 ppm/C or better. Rows labeled dHTCR and dCTCR give the difference in TCR between 0.25 and 1.25 mm resistors after sequential firing and cofiring with the driver doped and undoped terminations. In general, the length effect of resistors as given by dHTCR and dCTCR in TABLES 5 and 6 is considerably reduced when driver doped terminations are used.

[0048] TiO_2 additions to the termination are more effective on a weight basis than Nb_2O_5 or MnO_2 in negatively biasing the TCR of short resistors in order to compensate for the positive TCR caused by Ag+ diffusion into the resistor. The examples show that 1 % TiO_2 added to the Ag terminations caused the TCR of the 0.25 mm resistors to change by more than -100 ppm/C.

[0049] Data in TABLE 6 shows that TCR driver additives to the termination to reduce length effect need not be limited to simple oxides such as TiO_2 , Nb_2O_5 , and MnOx . Compounds of Ti, Nb, W, Mn are equally effective. As shown in TABLE 6, additions of MnTiO_3 , TiC , Ag_2WO_4 , NbH , and TiH_2 to termination A resulted in a reduced length effect compared to the undoped A termination. Small TiH_2 additions to the termination were found to be particularly effective in reducing the length effect of the resistor. TiH_2 decomposed during firing to Ti metal which alloys with the Ag termination. It is believed that the H_2 evolved provides a reducing atmosphere which may help to inhibit formation and diffusion of Ag+ into the resistor. This mechanism coupled with the strong TCR driver contribution from TiO_2 is very effective in minimizing length effect in the resistor.

[0050] Referring to Figure 3, the addition of metallic reducing agents such as W, Wsi_2 , and Cr in combination with TiH_2 , to the Ag termination (Ag termination compositions F, G, I found in TABLE 1) were also found to be effective in controlling length effect in short RuO_2 resistors. Metallic additions permitted a reduction in the amount of TiH_2 required in order to improve length effect and allowed fine tuning of length effect behavior as shown in Curves F, G, I in Figure 3.

[0051] Figure 3 shows the HTCR as a function of resistor length for a nominal 10 ohm resistor R1 sequentially fired over various Ag-rich terminations. The HTCR of R1 terminated with composition A increases as resistor length decreases (Curve A) which is typically observed behavior. However, curves for compositions E, F, G and I (found in TABLE 1) are representative of the current invention and show that the length effect can be substantially reduced or nearly eliminated by suitable additions to the Ag termination.

[0052] It should be noted the MnO_2 additions were not effective in negatively biasing the TCR of R2 because this 10 ohm resistor contains significant amounts of MnO and is already saturated, therefore, additional MnO_2 from the termination had little effect on the length effect of the resistor.

[0053] Figure 4 illustrates an improvement in length effect that can be obtained by practicing the present invention. The figure compares the length effect of a 10 ohm resistor terminated with a standard silver termination (Termination A) to the length effect obtained with a TiH_2 doped Ag termination of the present invention.

Claims

1. A thick film silver termination composition comprising, based on total composition:

- a. 60-80% wt. silver powder;
 - b. 1-15% wt. fine particles of glass binder having a softening point of 400 to 650°C and an absolute viscosity of less than 10^6 poise at firing temperature;
 - c. 1-5% wt. negative TCR driver; and
- wherein a, b, and c are dispersed in an organic vehicle.

2. A thick film silver termination composition comprising, based on total composition:

- a. 60-80% wt. silver powder;
 - b. 1-15% wt. fine particles of glass binder having a softening point of 400 to 650°C and a absolute viscosity of less than 10^6 poise at firing temperature;
 - c. 1-5% wt. hydrides of metals of the fourth and fifth groups of the periodic table; and
- wherein a, b, and c are dispersed in an organic vehicle.

3. A thick film silver termination composition comprising, based on total composition:

- a. 60-80% wt. silver powder;
 - b. .1-15% wt. fine particles of glass binder having a softening point of 400 to 650°C and an absolute viscosity of less than 10^6 poise at firing temperature;
 - c. .1-5% wt. metallic powders selected from the group consisting of Ti, Nb, Mn, Fe, Co, Cr, W, Mo, V, and Sb; and
- wherein a, b, and c are dispersed in an organic vehicle.

4. The composition of Claim 1 wherein the negative TCR drivers are selected from the group of oxides of Ta, Ti, Nb, Mn, Fe, Co, Cr, W, Mo, V and Sb.

5. The composition of Claim 2 wherein the hydrides of metals are selected from the group consisting of TiH_2 , ZrH_2 , HfH_2 , CbH_2 , ThH_4 and TaH.

6. The composition of Claim 1 further comprising metallic powders selected from the group consisting of Ti, Nb, Mn, Fe, Co, Cr, W, Mo, V, and Sb.

7. The composition of Claim 2 further comprising metallic powders selected from the group consisting of Ti, Nb, Mn, Fe, Co, Cr, W, Mo, V, and Sb.

8. The composition of Claim 1 wherein the glass binder is a lead bismuth borate glass.

9. The composition of Claim 2 wherein the glass binder is a lead bismuth borate glass.

10. The composition of Claim 3 wherein the glass binder is a lead bismuth borate glass.

11. The composition of Claim 1 wherein the glass binder comprises .1-10% wt.

12. The composition of Claim 2 wherein the glass binder comprises .1-10% wt.

13. The composition of Claim 3 wherein the glass binder comprises .1-10% wt.

14. The composition of Claim 1 wherein the firing temperature is in the range of 800 -900°C.

15. The composition of Claim 2 wherein the firing temperature is in the range of 800 -900°C.

16. The composition of Claim 3 wherein the firing temperature is in the range of 800 -900°C.

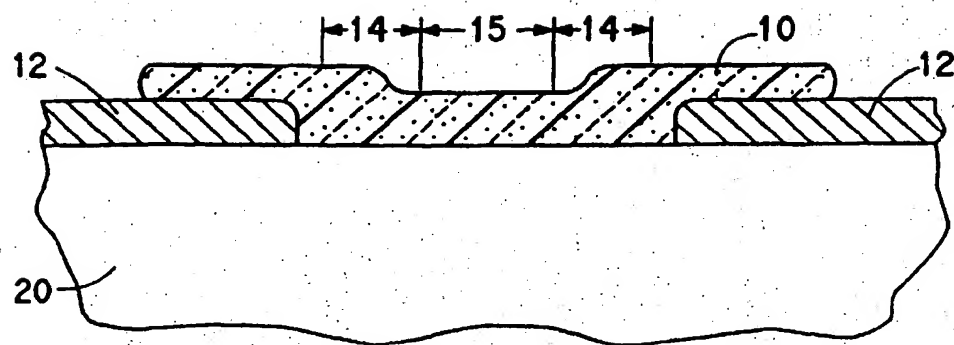


FIG. 1

FIG. 2

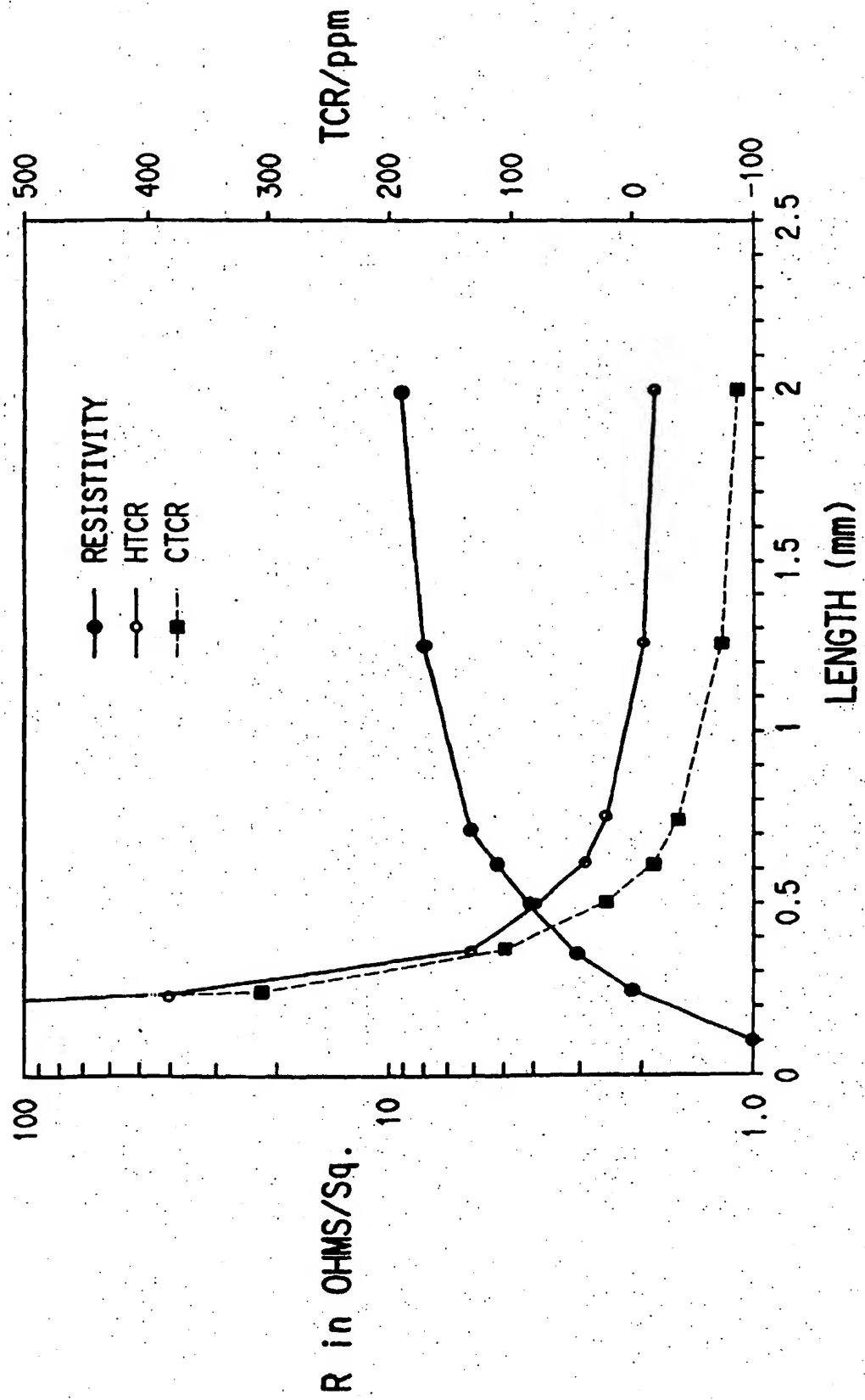


FIG. 3

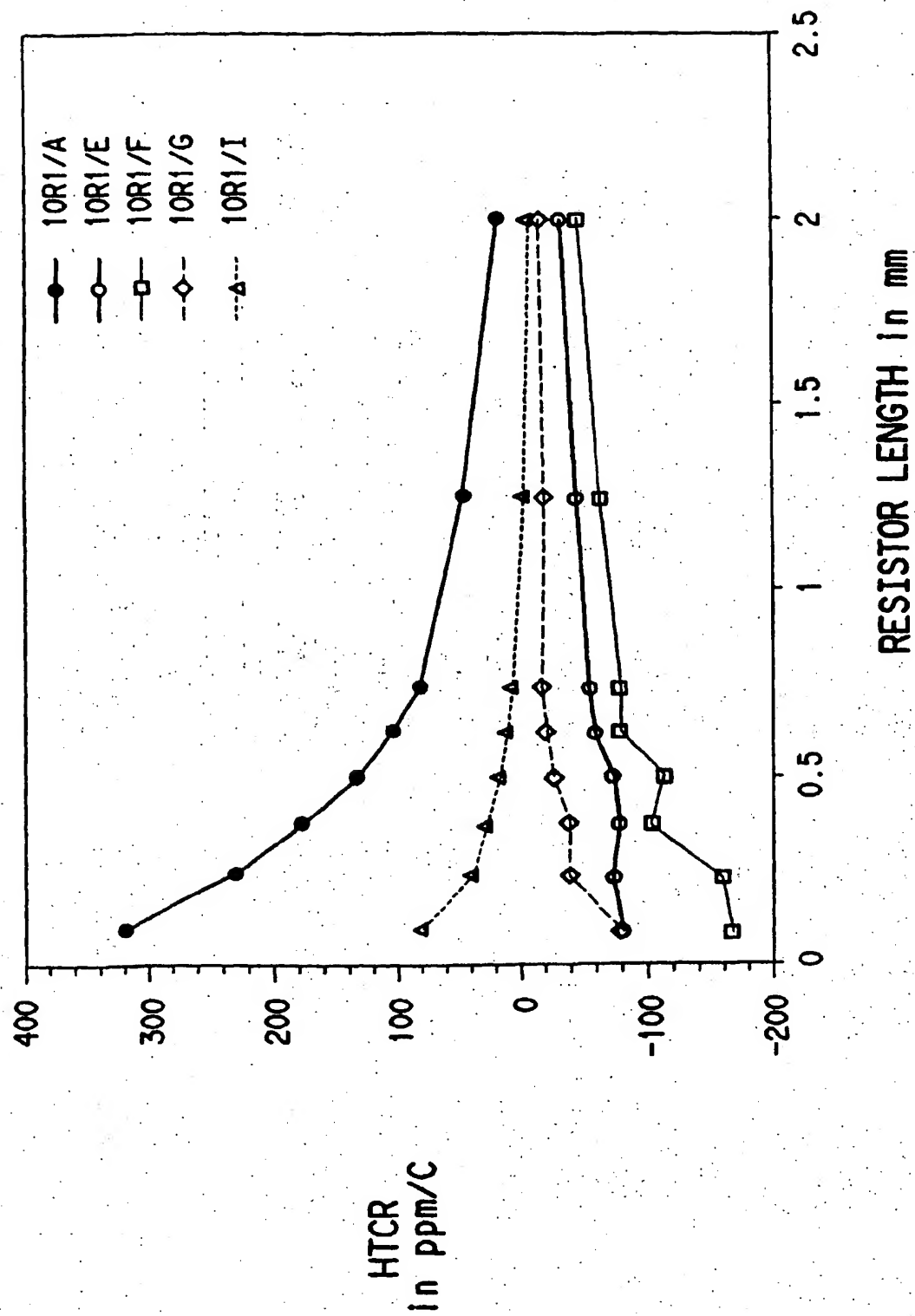
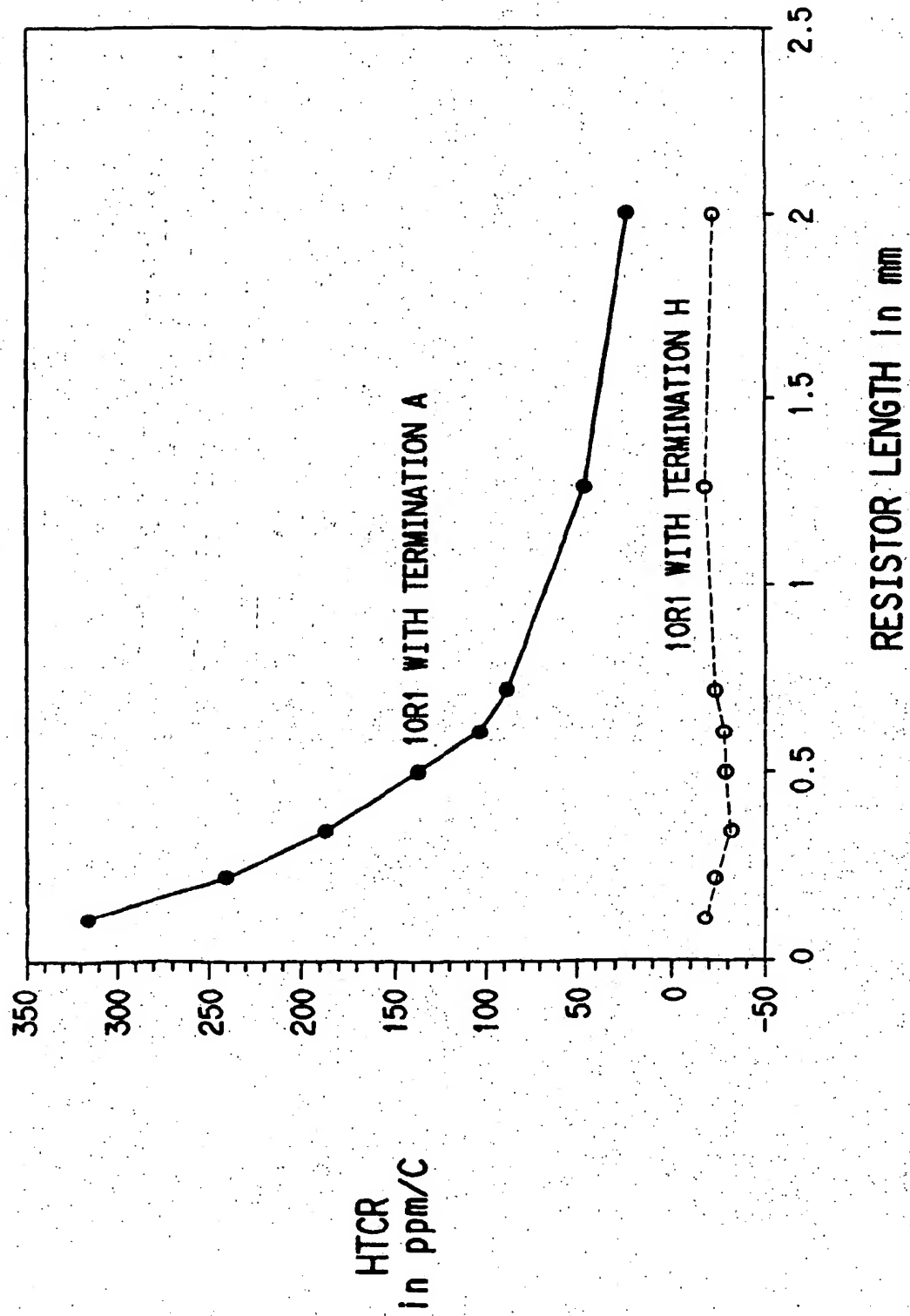


FIG. 4





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Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.6)
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Y	* abstract * * example 9; table 1 *	10	
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The present search report has been drawn up for all claims			
Place of search THE HAGUE		Date of completion of the search 20 October 1998	Examiner Rosenberger, J
<p>CATEGORY OF CITED DOCUMENTS</p> <p>X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document</p> <p>T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document</p>			

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Application Number
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DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.6)
X	<p>DATABASE WPI Section Ch, Week 7913 Derwent Publications Ltd., London, GB; Class A82, AN 79-24588B XP002081380 -& JP 54 022596 A (MURATA MFG CO LTD) , 20 February 1979 * abstract * * examples 7,8; tables 1,2 *</p>	1,3,4,6	
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			TECHNICAL FIELDS SEARCHED (Int.Cl.6)
The present search report has been drawn up for all claims			
Place of search THE HAGUE		Date of completion of the search 20 October 1998	Examiner Rosenberger, J
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